

# TUZ Call for Papers 2025



Berlin, 23. bis 25. February 2025

## 37. ITG / GMM / GI - Workshop on Test and Reliability of Circuits and Systems

### Programmkomitee

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University Paderborn  
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Kyushu Institute of Technology  
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V. Petrovic  
HOL Design House  
L. Bolzani Poehls  
RWTH Aachen  
J. Polian  
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Univ Erlangen-Nürnberg  
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NXP Semiconductors Germany GmbH  
H. Schmidt  
IBM Deutschland GmbH  
M. Schözel  
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J. Sepulveda  
Airbus Defence and Space  
M. Tahoori  
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Siemens Digital Industries Software  
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The workshop "Test Methods and Reliability of Circuits and Systems" is the most important German forum for discussing trends, results and current problems in the field of testing, diagnostics and reliability of digital, analog, mixed-signal and RF circuits. The exchange of ideas is an important concern of the workshop. Contributions from both industrial practice and research institutions are welcome. We welcome highly practice-related experience reports and results as well as contributions on theoretical topics from the following areas, among others:

- adaptive systems (e.g. self-repair, self-healing, self-awareness)
- automatic test-equipment, test automation, test programs und test modeling
- defect- und fault models
- diagnosis of failure causes
- fault tolerance, resilience, robust and radiation-hard systems
- functional safety
- Hardware-oriented test und hardware-oriented security
- Statistical and AI-learning for test and reliability
- Test und Simulation of Mixed-Signal, HF- and Analog-circuit-test
- Test generation, fault simulation, Selftest und Online-Test
- Test-oriented design, DfT methods
- Test costs and quality
- Test standards, e.g. IEEE 1149.x, IEEE 1687.x, IEEE 1838

The workshop will take place in the Müggelseeperle conference hotel in Berlin-Köpenick and is organized by the Technical University of Wildau in cooperation with the IHP. The event is planned to be held entirely in person. Interested parties are asked to submit a summary of their contribution of a maximum of 2 pages via the workshop homepage. The contribution should describe the purpose of the work, the novelty and aspects of the application. Accepted contributions will be included in the informal workshop handout upon request. The contribution can be extended to 4 pages for this purpose.



### Workshop-Homepage

[www.tuz-workshop.de](http://www.tuz-workshop.de)

### Submission-Page

<https://easychair.org/conferences/?conf=tuz25>

### Important Dates

**Submission of Abstracts: 10. Nov. 2024**

Submission of final Contributions: 17. Nov.2024

Author Notification: 20. Dec.2024

Camera-ready-paper: 18. Jan. 2025

### General Chair

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### Program Chair

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### Veranstalter

GIFA3.5/GMMFA6.5/ITGFA8.2RSSKooperationsgemeinschaft Rechnergestützter Schaltungs- und Systementwurf

